Docket No.: SUSU121258 1/10 - 20 X address decoder - 32 \_10 33 -11 31 Y address decoder 34 (Control signal) 40 FIG.1 - <u>11</u> Resistance measurement pattern area 11a-Capacity measurement pattern area ~11b n-type MOS transistor 11cmeasurement pattern area Ring oscillator √11e measurement p-type MOS pattern area transistor 11dmeasurement F I G. 2 pattern area

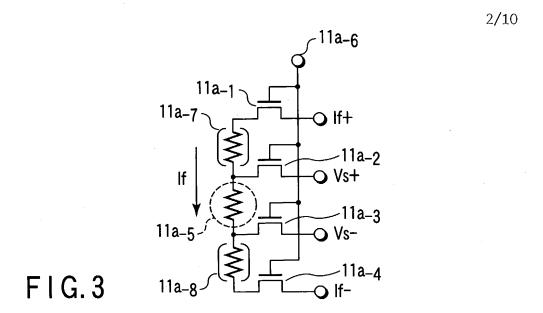
Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION

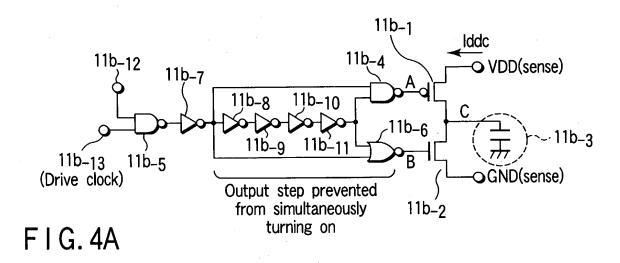
S. Ohkawa et al.

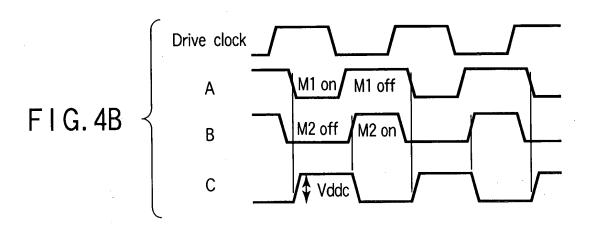
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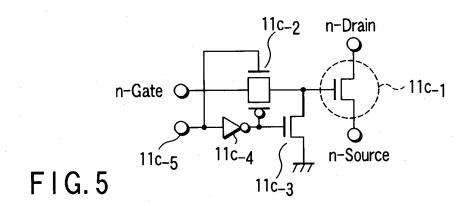


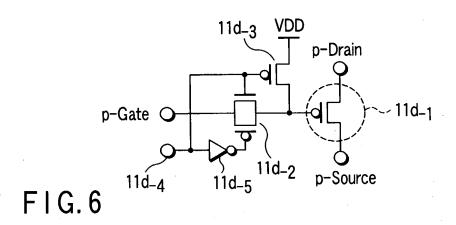
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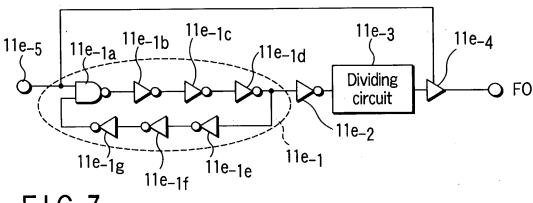
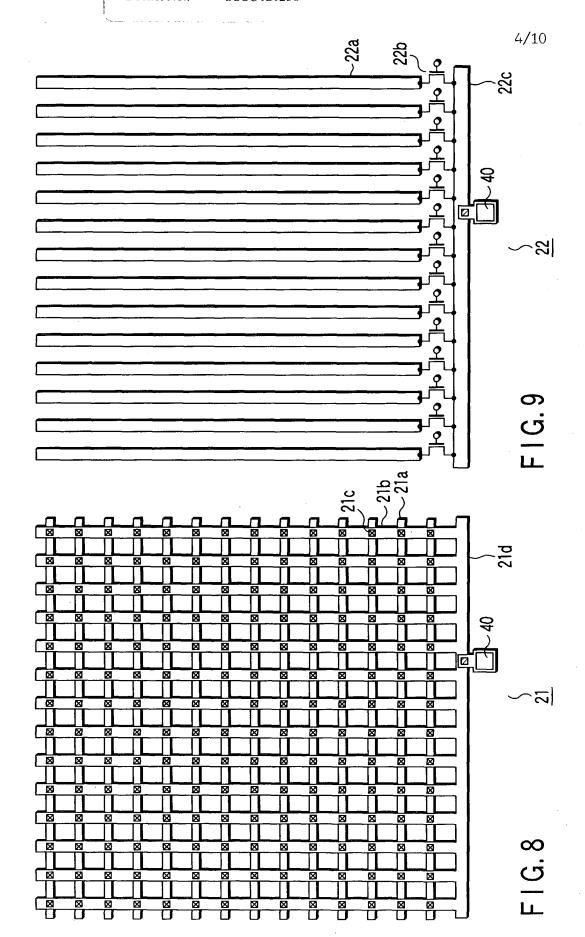


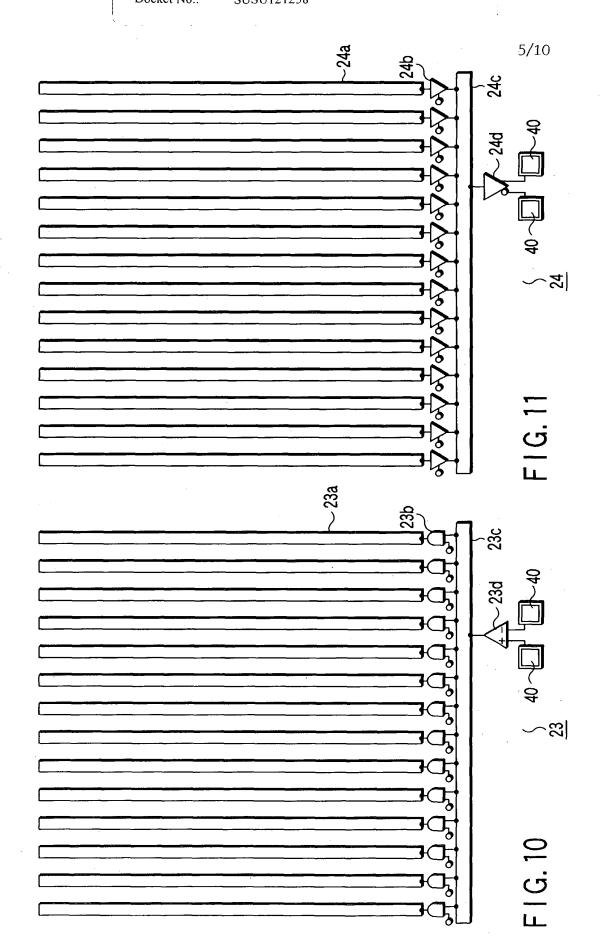
FIG.7

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S. Ohkawa et al.

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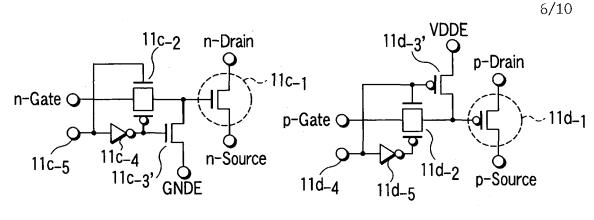
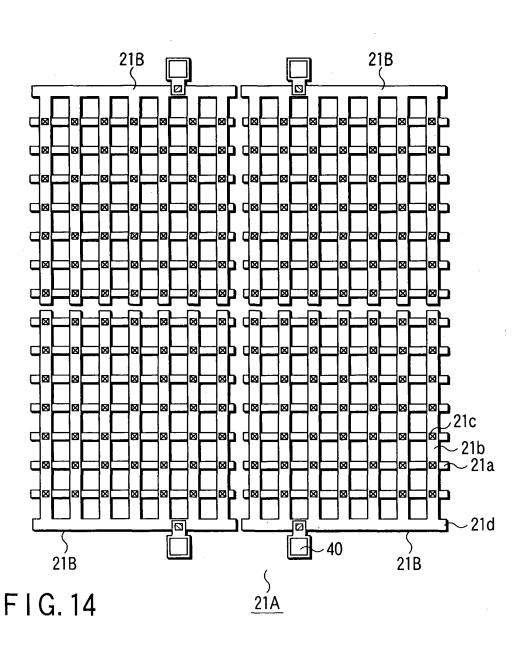


FIG. 12

FIG. 13

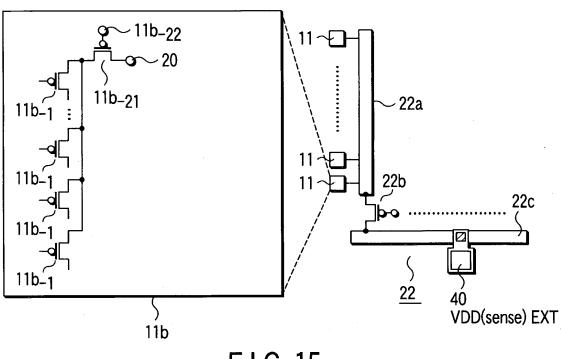


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F I G. 15

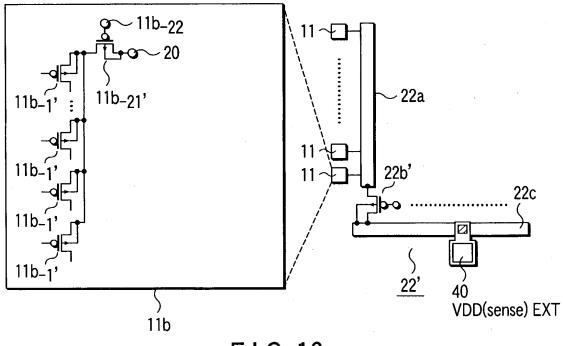


FIG. 16

Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION APPARATUS S. Ohkawa et al. SUSU121258 Inventors: Docket No.: 8/10 Dividing circuit

11e-5

11e-2

Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION **APPARATUS** Inventors: S. Ohkawa et al. Docket No.: SUSU121258 9/10 MAU MAU MAU MAU MAU MAU MAU MAU **~11** MAU MAU MAU MAU MAU MAU MAU MAU - 10 FIG. 18A MAU - 10A MAU MAU MAU 11A'~ MAU MAU MAU MAU - 11A 11A'~ MAU MAU MAU MAU ~ 11A' MAU MAU MAU MAU 11A'~ FIG. 18B 11B MAU -11B' MAU MAU MAU MAU - 10B

FIG. 18C

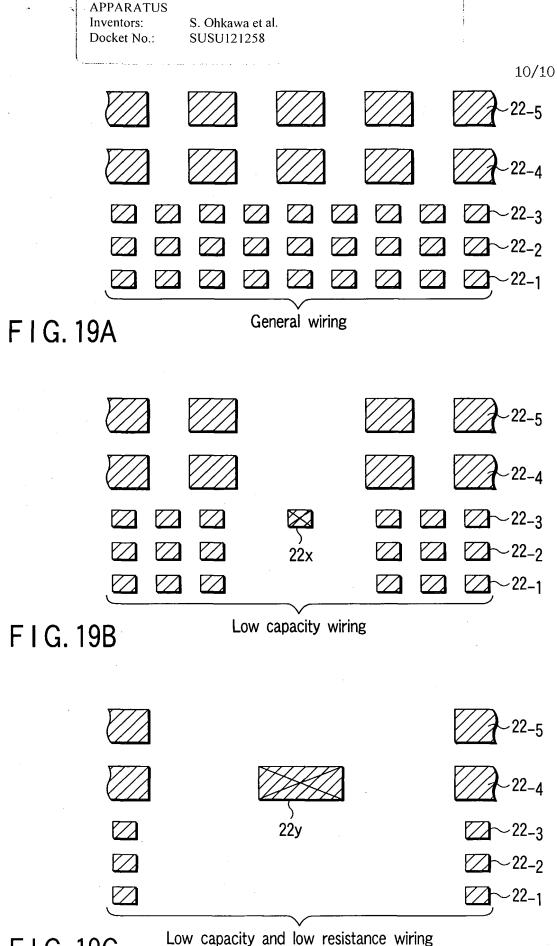


FIG. 19C Low capacity and I